



# Power MOSFETS

## DATASHEET

**LM60107NHP3A**

N-Channel  
Enhancement Mode MOSFET

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Quality Management Systems  
ISO 9001:2015 Certificate

## N-Channel Enhancement Mode MOSFET

### Pin Description

TO-220-3L	Symbol	Symbol	N-Channel	Unit
			$V_{DSS}$	60 V
			$R_{DS(ON)-Max}$	10.7 mΩ
			$ID$	88 A

### Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS Tested

### Product Summary

- Power Management in DC/DC Converters
- Power Load Switching Application

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM60107NHP3A	TO-220-3L	Tube	50 / Tube	60107 □□□□□□

Note : □□□□□□ = Lot Code

### Absolute Maximum Ratings ( $T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
$V_{DSS}$	Drain-Source Voltage	60	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	
$T_J$	Maximum Junction Temperature	150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$I_S$	Diode Continuous Forward Current	$T_c=25^\circ\text{C}$	A
$I_{DM}^{\text{(1)}}$	Pulse Drain Current Tested	$T_c=25^\circ\text{C}$	A
$I_D$	Continuous Drain Current	$T_c=25^\circ\text{C}$	A
		$T_c=100^\circ\text{C}$	
$P_D$	Maximum Power Dissipation	$T_c=25^\circ\text{C}$	W
		$T_c=100^\circ\text{C}$	
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$	A
		$T_A=70^\circ\text{C}$	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	W
		$T_A=70^\circ\text{C}$	
$I_{AS}^{\text{(2)}}$	Avalanche Current, Single pulse	L=0.1mH	A
$E_{AS}^{\text{(2)}}$	Avalanche Energy, Single pulse	L=0.5mH	mJ
		L=0.1mH	
		L=0.5mH	

### Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	$^\circ\text{C/W}$
$R_{\theta JA}^{\text{(3)}}$	Thermal Resistance-Junction to Ambient	Steady State	$^\circ\text{C/W}$

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature  $150^\circ\text{C}$

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz

**N-Channel Electrical Characteristics** ( $T_J=25^\circ\text{C}$  Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_{DS}=250\mu\text{A}$	60	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=48\text{V}, V_{GS}=0\text{V}$	-	-	1	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu\text{A}$	2	2.8	4	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	-	-	$\pm 100$	$\text{nA}$
$R_{DS(\text{ON})}^{\text{(4)}}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}, I_{DS}=15\text{A}$	-	8.8	10.7	$\text{m}\Omega$
		$V_{GS}=6\text{V}, I_{DS}=8\text{A}$	-	12.3	16	
$g_{fs}$	Forward Transconductance	$V_{DS}=5\text{V}, I_{DS}=15\text{A}$	-	20	-	S
<b>Dynamic Characteristics</b> <sup>(5)</sup>						
$R_G$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V},$ Freq.=1MHz	-	2.6	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V},$ $V_{DS}=30\text{V},$ Freq.=1MHz	-	2490	-	$\text{pF}$
$C_{oss}$	Output Capacitance		-	179	-	
$C_{rss}$	Reverse Transfer Capacitance		-	114	-	
$t_{d(\text{ON})}$	Turn-on Delay Time	$V_{GS}=10\text{V}, V_{DS}=30\text{V},$ $I_D=1\text{A}, R_{GEN}=6\Omega$	-	17	-	$\text{nS}$
$t_r$	Turn-on Rise Time		-	14	-	
$t_{d(\text{OFF})}$	Turn-off Delay Time		-	58	-	
$t_f$	Turn-off Fall Time		-	38	-	
$Q_g$	Total Gate Charge	$V_{GS}=6\text{V}, V_{DS}=30\text{V}$ $I_D=15\text{A}$	-	32	-	$\text{nC}$
$Q_g$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V},$ $I_D=15\text{A}$	-	52	-	
$Q_{gs}$	Gate-Source Charge		-	20	-	
$Q_{gd}$	Gate-Drain Charge		-	12	-	
<b>Source-Drain Characteristics</b>						
$V_{SD}^{\text{(4)}}$	Diode Forward Voltage	$I_{SD}=10\text{A}, V_{GS}=0\text{V}$	-	0.8	1.1	V
$t_{rr}$	Reverse Recovery Time	$I_F=10\text{A}, V_R=0\text{V}$ $dI_F/dt=100\text{A}/\mu\text{s}$	-	26	-	$\text{nS}$
$Q_{rr}$	Reverse Recovery Charge		-	32	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$ , duty cycle $\leq 2\%$ ).

Note ⑤ : Guaranteed by design, not subject to production testing.

## N-Channel Typical Characteristics

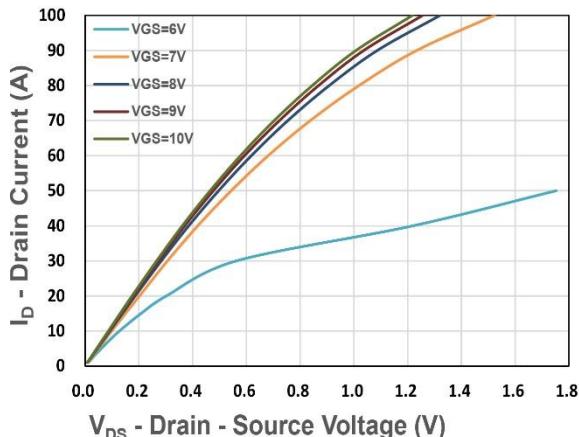


Figure 1. Output Characteristics

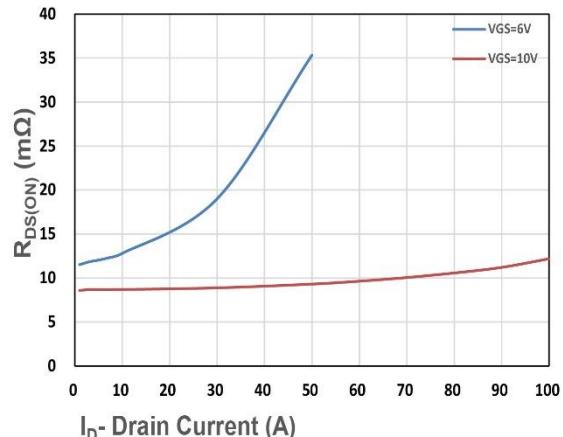


Figure 2. On-Resistance vs. ID

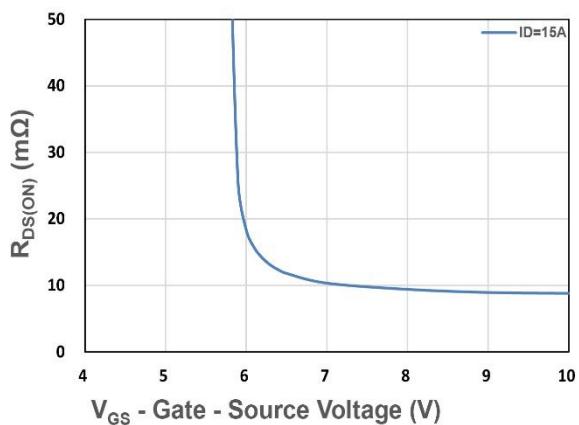


Figure 3. On-Resistance vs. VGS

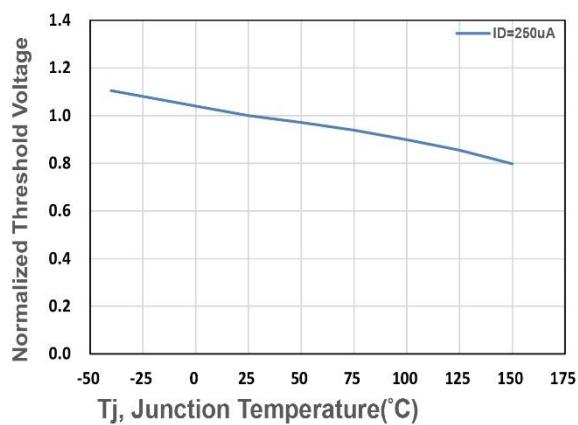


Figure 4. Gate Threshold Voltage

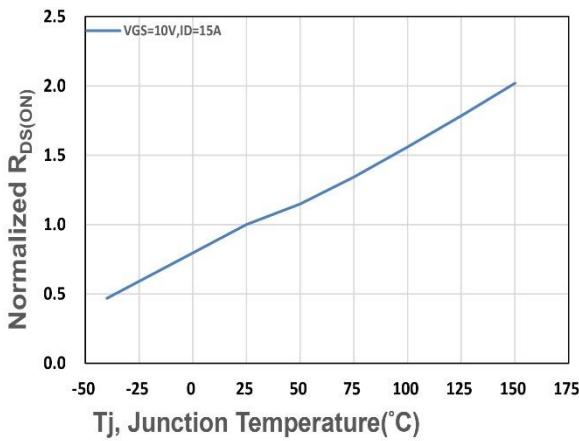


Figure 5. Drain-Source On Resistance

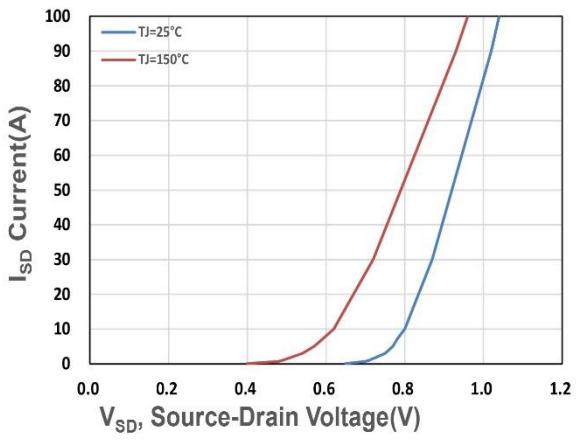


Figure 6. Source-Drain Diode Forward

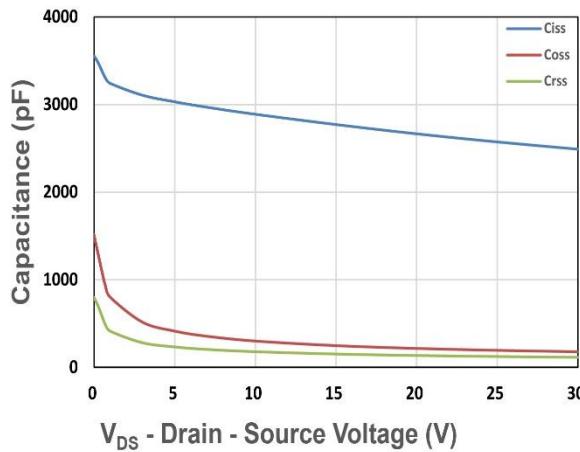


Figure 7. Capacitance

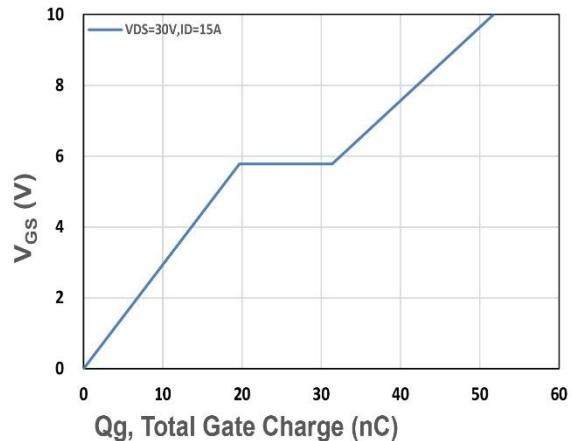


Figure 8. Gate Charge Characteristics

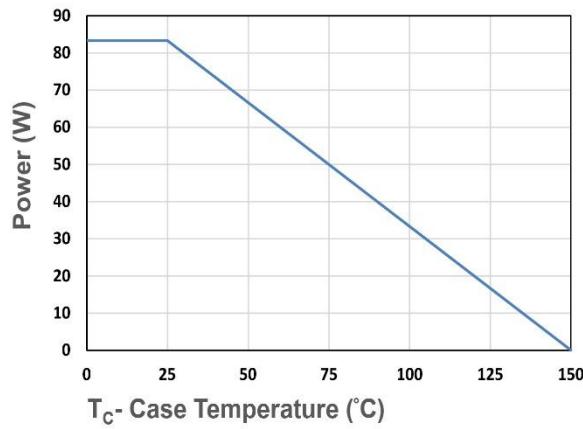


Figure 9. Power Dissipation

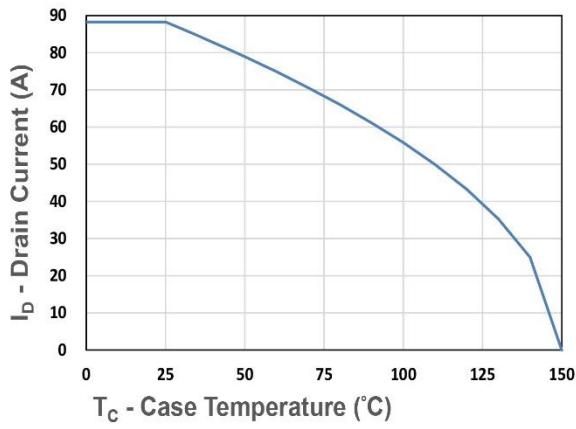


Figure 10. Drain Current

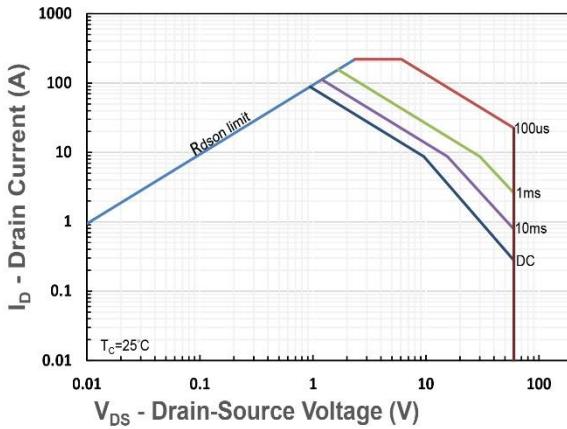


Figure 11. Safe Operating Area

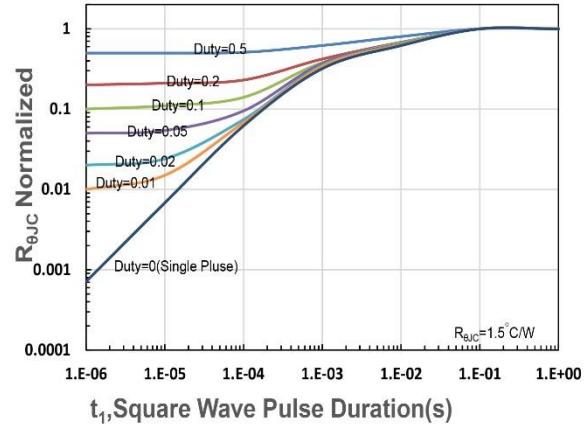


Figure 12. R<sub>θJC</sub> Transient Thermal Impedance